

CMOS Design Project: 7T MCPL SRAM Cell



Indian Institute of Information Technology,

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ECL 312: CMOS Design

A Project Report on: 7T MCPL SRAM Cell and 2x2 SRAM Array

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Project Overview

This repository contains the design, simulation, and analysis of a **7T MCPL (Multi-Clock Power Logic) SRAM cell** and its **2x2 SRAM array**, utilizing adiabatic logic for enhanced power efficiency. This project compares the performance of a conventional 6T SRAM and the novel 7T MCPL SRAM design under 180nm CMOS technology. Tools like WinSpice, Microwind, and Cadence Virtuoso were used for circuit layout and Static Noise Margin (SNM) analysis.

Adiabatic logic, with its energy-recycling capabilities, is employed in the 7T MCPL SRAM cell to achieve significant power savings compared to traditional CMOS designs.

Objectives

1. **Design and simulate** a 7T SRAM cell using **MCPL adiabatic logic**.
2. Implement a **2x2 SRAM array** using the 7T MCPL design.
2. Compare the performance of the **6T SRAM** and **7T MCPL SRAM** designs.
3. Demonstrate power and energy savings achieved by the MCPL design under **180nm technology**.
4. Simulate **read and write operations** of both 6T and 7T SRAM cells.
5. Analyze the **Static Noise Margin (SNM)** of both designs, using **Cadence Virtuoso** for SNM plotting.

Design Description

6T SRAM Cell

The 6T SRAM cell is a well-established design, featuring two cross-coupled inverters that store data. It consists of: - **6 transistors** (4 for inverters, 2 for access transistors). - Stable operation but higher power dissipation compared to the 7T MCPL design.

7T MCPL SRAM Cell

The 7T MCPL design incorporates **adiabatic logic** principles, specifically using **Multi-Clock Power Logic (MCPL)** to reduce power dissipation: - **7 transistors**, with the extra transistor providing better stability and noise

immunity. - **AC power supply** through MCPL to reuse energy, significantly lowering power consumption. - Control signals **S1** and **S2** manage the MCPL node, transitioning between high, low, and floating states based on the operating mode.

SystemVerilog Code Snippets

design.sv

```
module SRAM(
    input [3:0] dataIn,      // 4-bit input data
    input [1:0] Addr,        // 2-bit address
    input CS, WE, RD, Clk,   // Chip Select, Write Enable, Read
    Enable, Clock
    output reg [3:0] Q       // 4-bit output for all SRAM locations
    (q1, q2, q3, q4)
);
    // 4 memory locations (4-bit each)
    reg [3:0] SRAMs [3:0]; // 4 memory locations (SRAM[0] to SRAM[3])

    // Initialize SRAM and outputs to 0 at startup
    initial begin
        SRAMs[0] = 4'b0000;
        SRAMs[1] = 4'b0000;
        SRAMs[2] = 4'b0000;
        SRAMs[3] = 4'b0000;
        Q = 4'b0000; // All outputs start as 0
    end

    // Write/Read operation and update Q
    always @(posedge Clk) begin
        if (CS == 1'b1) begin
```

```

        if (WE == 1'b1 && RD == 1'b0) begin
            // Write to SRAM at the specified address
            SRAMs[Addr] <= dataIn;
            Q <= dataIn; // Q reflects the value written to the
SRAM
        end else if (RD == 1'b1 && WE == 1'b0) begin
            // Read from SRAM at the specified address
            Q <= SRAMs[Addr]; // Q reflects the current data at
the address
        end
    end
end

// Always update the output Q to reflect the state of all SRAMs
always @(*) begin
    Q = {SRAMs[3], SRAMs[2], SRAMs[1], SRAMs[0]}; // Concatenate
SRAMs to form Q
end
endmodule

```

testbench.sv

```

module SRAM_tb();
    // Inputs
    reg [3:0] dataIn; // 4-bit data input
    reg [1:0] Addr; // 2-bit address for 4 locations
    reg CS, WE, RD, Clk;

    // Outputs
    wire [3:0] Q; // 4-bit output for all SRAM locations (q1,
q2, q3, q4)

```

```

// Instantiate the Unit Under Test (UUT)
SRAM uut (
    .dataIn(dataIn),
    .Addr(Addr),
    .CS(CS),
    .WE(WE),
    .RD(RD),
    .Clk(Clk),
    .Q(Q)
);

initial begin
    // Initialize Inputs
    dataIn = 4'b0000;
    Addr = 2'b00;    // Start with address 00
    CS = 1'b0;
    WE = 1'b0;
    RD = 1'b0;
    Clk = 1'b0;

    // Create the VCD file and dump the variables
    $dumpfile("waveform.vcd"); // Name of the VCD file
    $dumpvars(0, SRAM_tb);      // Dump all variables in the
testbench

    // Wait for global reset to finish
    #100;

```

```

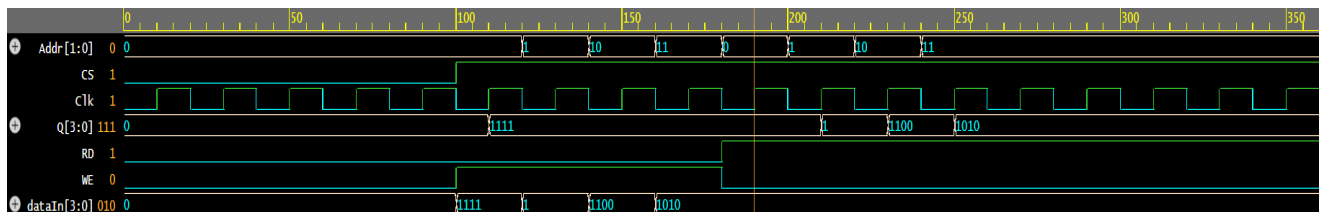
// Test Writing to the SRAM cells
CS = 1;
WE = 1;
RD = 0;
dataIn = 4'b1010;
Addr = 2'b00;
#10 Clk = ~Clk;
#10 Clk = ~Clk;

// Test Reading from the SRAM cells
WE = 0;
RD = 1;
#10 Clk = ~Clk;
#10 Clk = ~Clk;

$finish;

end
endmodule

```



Simulation Files

Below are snippets of the circuit files used for simulation in **WinSpice**:

6T SRAM Write Mode

```

.model nmod nmos level=54 version=4.7
.model pmod pmos level=54 version=4.7

```

```

.subckt inverter 1 2 3
M1 3 1 0 0 pmod w=100u l=10u
M2 3 1 2 2 nmod w=100u l=10u
.ends

Vdd 2 0 dc 5
Vwl 6 0 dc 5

Vbit 7 0 pulse(0 5 0 0 0 100m 200m)
Vbitbar 8 0 pulse(5 0 0 0 0 100m 200m)

Xq 1 2 3 inverter
Xqbar 3 2 1 inverter

M5 7 6 3 3 pmod w=100u l=10u
M6 8 6 1 1 pmod w=100u l=10u

.tran 0.1m 400m
.control
run
plot v(7) v(8) v(3) v(1)
.endc
.end

```

7T MCPL SRAM Write Mode

```

.model nmod nmos level=54 version=4.7
.model pmod pmos level=54 version=4.7
.subckt inverter G Sp D
M1 D G 0 0 nmod w=100u l=10u
M2 D G Sp Sp pmod w=200u l=10u
.ends
Vdd 2 0 dc 5
Vwl 6 0 dc 5
Vwlb 9 0 dc 0
Vbit 7 0 dc 5
Vbitbar 8 0 dc 0
Vs1 13 0 pulse(0 5 0 0 0 200m 400m)
Vs2 11 0 pulse(0 5 0 0 0 100m 200m)
Xq 1 10 3 inverter
Xqbar 3 10 1 inverter
M5 7 6 3 3 nmod w=100u l=10u
M6 8 6 1 1 nmod w=100u l=10u
M7 3 9 3 0 nmod w=100u l=10u
M9 10 11 2 2 pmod w=200u l=10u
M10 10 13 0 0 nmod w=100u l=10u
.tran 0.1m 400m

```

```
.control
run
plot v(7) v(8) v(3) v(1) v(13) v(11)
.endc
.end
```

7T MCPL SRAM 2x2 Array

```
*** 7T MCPL SRAM 2x2 Array ***
* NMOS and PMOS Models *
.model nmod nmos level=54 version=4.7
.model pmod pmos level=54 version=4.7
* Inverter Subcircuit *
.subckt inverter in out vdd
M1 out in vdd vdd pmod w=200u l=10u
M2 out in 0 0 nmod w=100u l=10u
.ends inverter
* Transmission Gate NAND Gate Subcircuit (for decoding) *
.subckt transmission_gate_nand a0 a1 a1_bar out
M1 out a1 a0 0 nmod w=100u l=10u
M2 out a1_bar a0 0 pmod w=200u l=10u
M3 out a1_bar 0 0 nmod w=100u l=10u
M4 out a1 0 0 pmod w=200u l=10u
.ends transmission_gate_nand

* Sense Amplifier Subcircuit *
.subckt sense_amp BL BL_bar OUT Vdd
Msa1 OUT BL 0 0 nmod w=100u l=10u
Msa2 OUT BL_bar Vdd Vdd pmod w=200u l=10u
.ends sense_amp

* Write Amplifier Subcircuit *
.subckt write_amp DATA BL BL_bar Vdd
Mw1 BL DATA 0 0 nmod w=100u l=10u
Mw2 BL_bar DATA Vdd Vdd pmod w=200u l=10u
.ends write_amp

* 7T MCPL SRAM Cell (Corrected subcircuit reference) *
.subckt sram_cell BL BL_bar WL WL_bar Vdd
Xinv1 BL BL_bar Vdd inverter
Xinv2 BL_bar BL Vdd inverter
M5 BL WL 0 0 nmod w=100u l=10u
M6 BL_bar WL 0 0 nmod w=100u l=10u
M7 BL WL_bar BL 0 nmod w=100u l=10u
.ends sram_cell

* Row Decoder Subcircuit (Corrected node connections) *
```



```

.subckt row_decoder a0 a1 a1_bar Vdd out
Xnand a0 a1 a1_bar out transmission_gate_nand
.ends row_decoder

* Column Decoder Subcircuit (Corrected node connections) *
.subckt col_decoder a0 a1 a1_bar Vdd out
Xnand a0 a1 a1_bar out transmission_gate_nand
.ends col_decoder

* Main Circuit for 2x2 SRAM Array *

Vdd 2 0 dc 5

* Wordline and Bitline Drivers *
VWL 6 0 dc 5
VWL_bar 9 0 dc 0
VBL 7 0 dc 5
VBL_bar 8 0 dc 0

* Row/Column Selection Pulses *
Vs1 13 0 pulse(0 5 0 0 0 200m 400m)
* Wordline select 1
Vs2 11 0 pulse(0 5 0 0 0 100m 200m)
* Wordline select 2
Vc1 15 0 pulse(0 5 0 0 0 200m 400m)
* Column select 1
Vc2 17 0 pulse(0 5 0 0 0 100m 200m)
* Column select 2

* 2x2 SRAM Array (Corrected subcircuit connections) *
Xsram1 7 8 6 9 2 sram_cell
Xsram2 7 8 13 9 2 sram_cell
Xsram3 7 8 6 17 2 sram_cell
Xsram4 7 8 13 17 2 sram_cell

* Row Decoder (Fixed parameter count) *
Xrow_decoder_1 6 13 11 2 out1 row_decoder
Xrow_decoder_2 6 17 11 2 out2 row_decoder

* Column Decoder (Fixed parameter count) *
Xcol_decoder_1 7 15 11 2 out3 col_decoder
Xcol_decoder_2 8 17 11 2 out4 col_decoder

* Sense Amplifier and Write Driver (Fixed node 10) *
V10 10 0 dc 0
* Grounding node 10 to fix floating issue

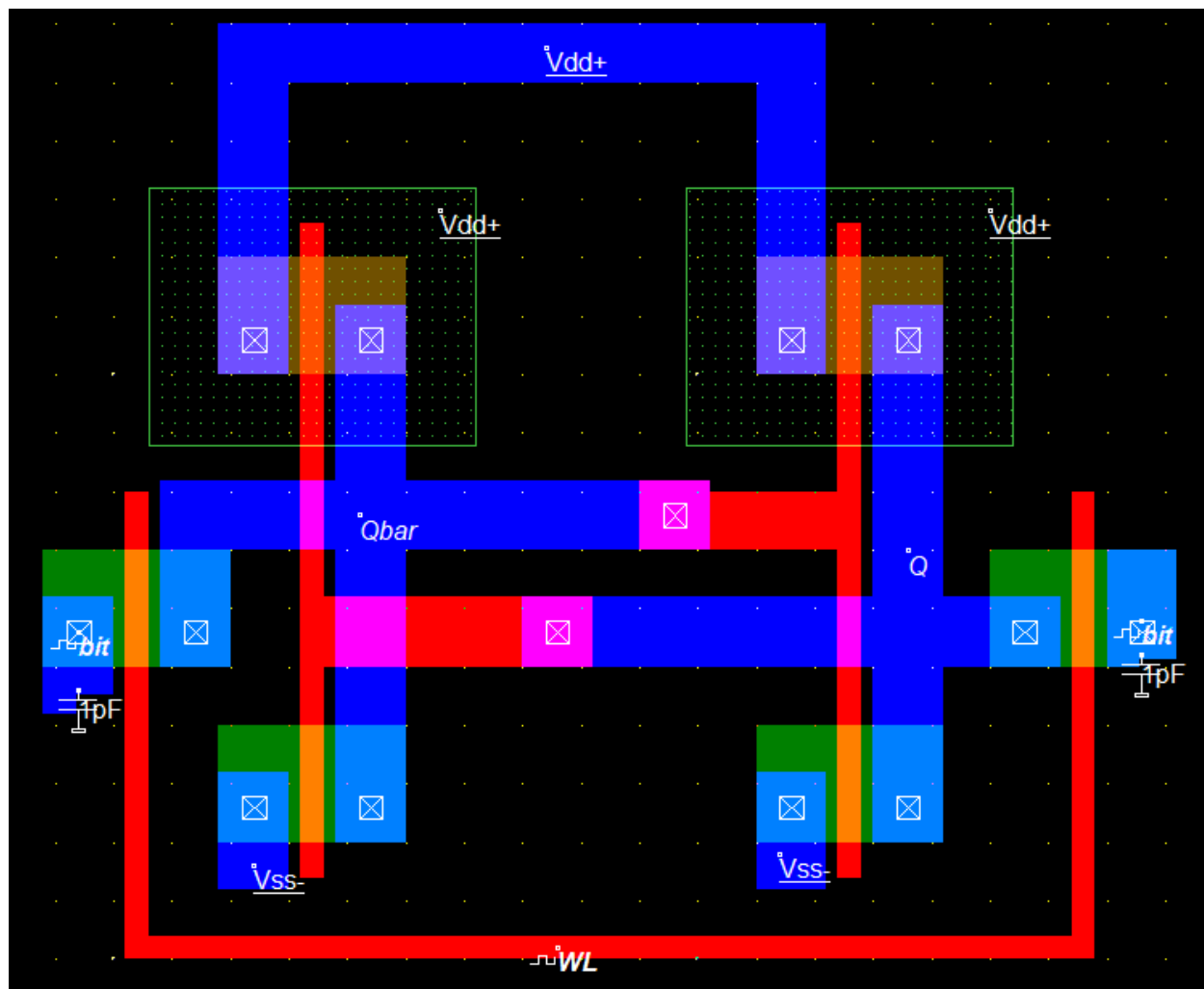
```

```
Xsense_amp 7 8 OUT 2 sense_amp
Xwrite_amp 10 7 8 2 write_amp
```

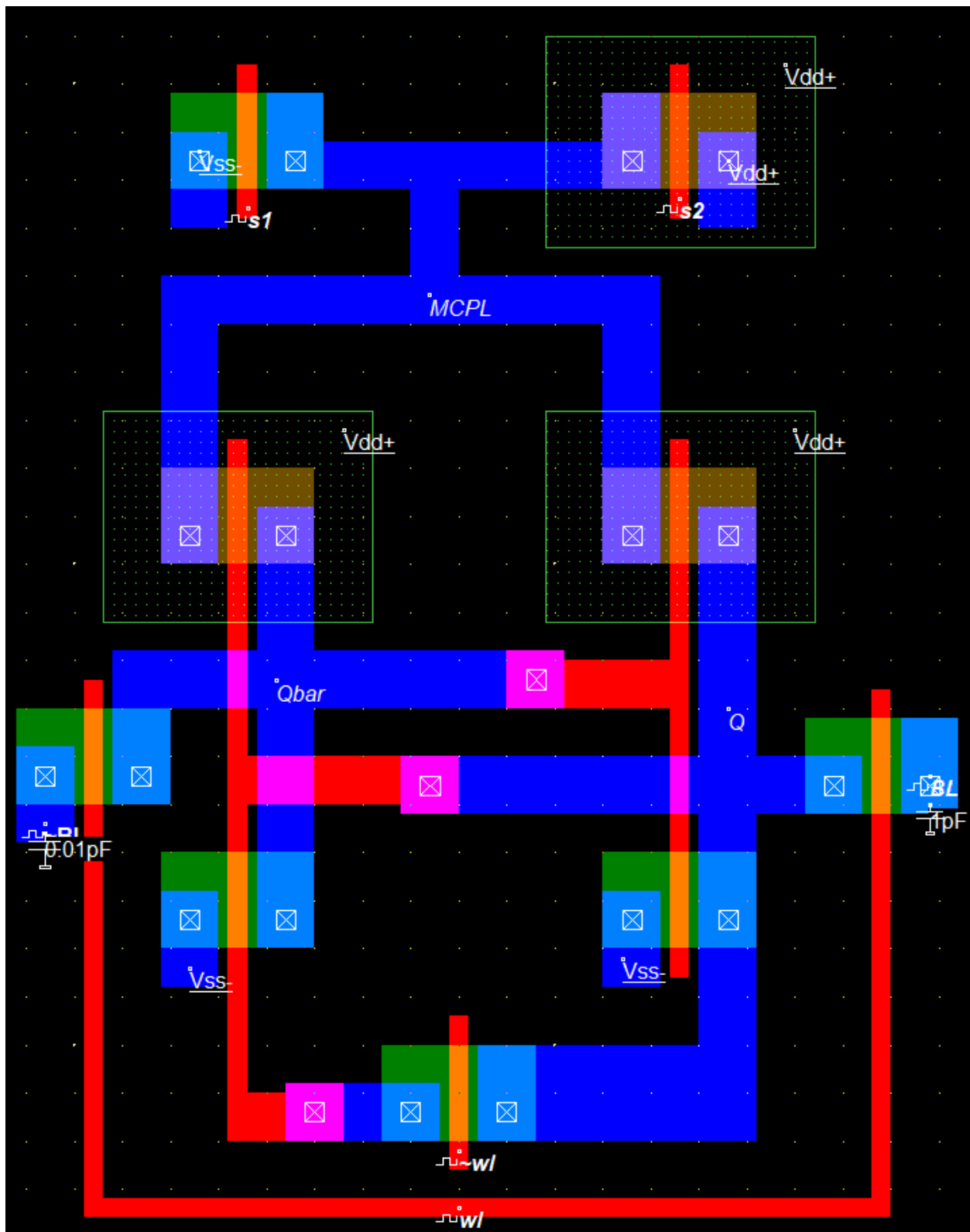
```
* Simulation Commands *
.tran 0.1m 400m
.control
run
plot v(7) v(8) v(OUT) v(10)
.endc
.end
```

Layout and Waveforms

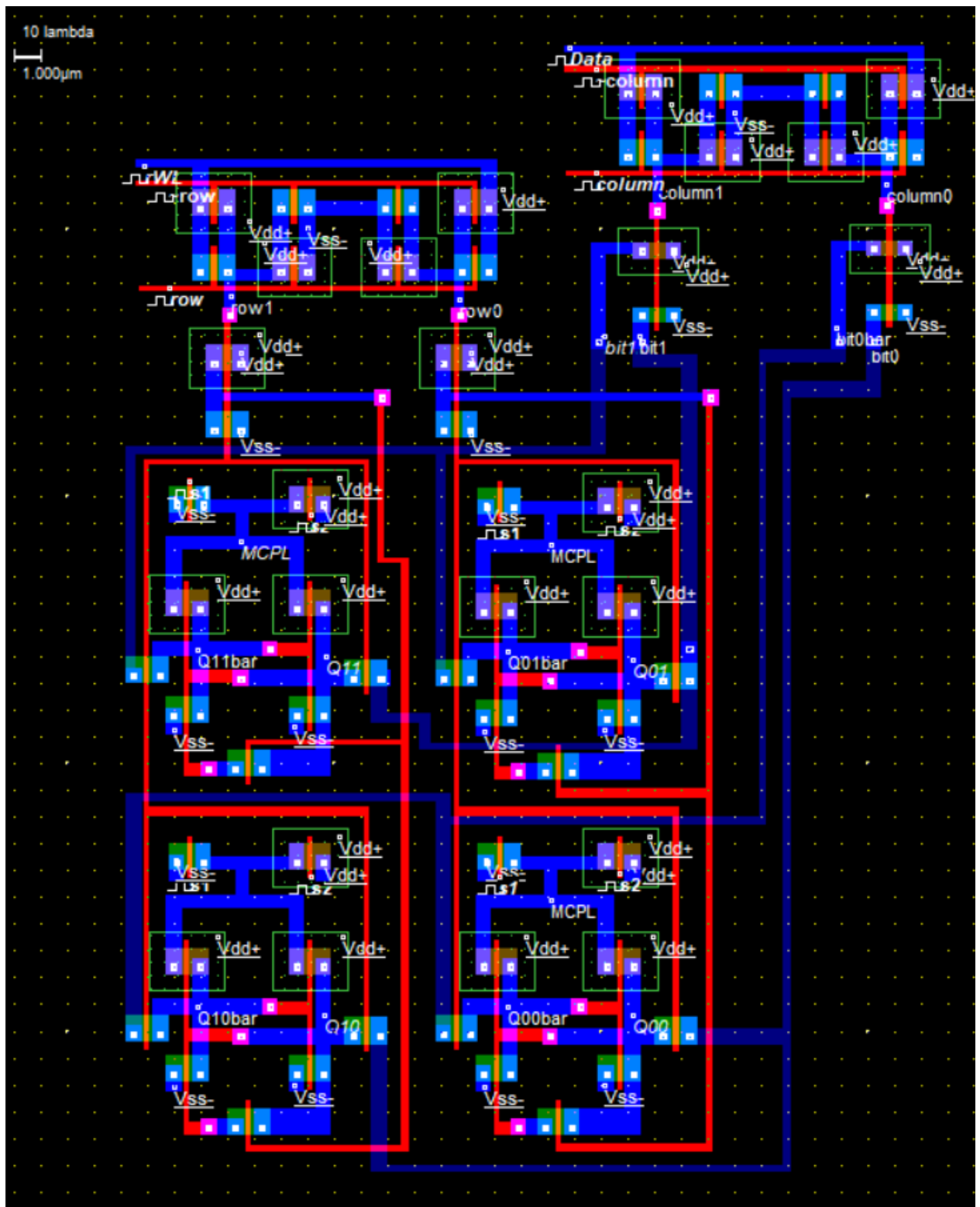
6T SRAM Layout



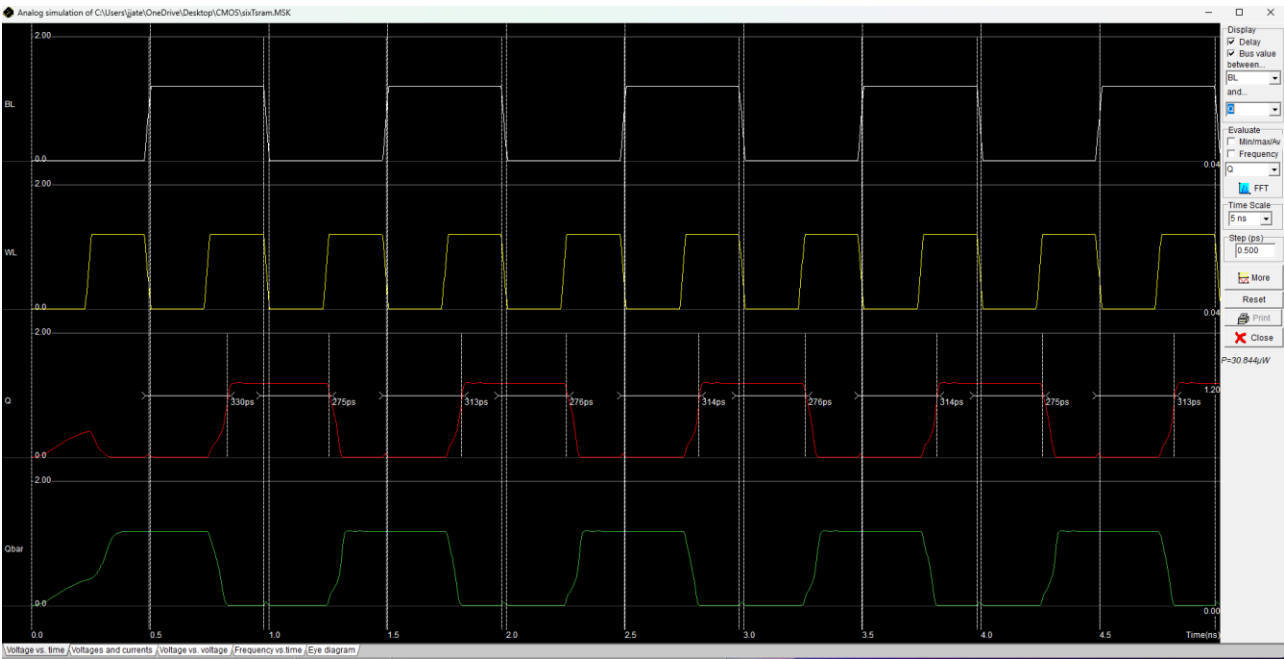
7T MCPL SRAM Layout



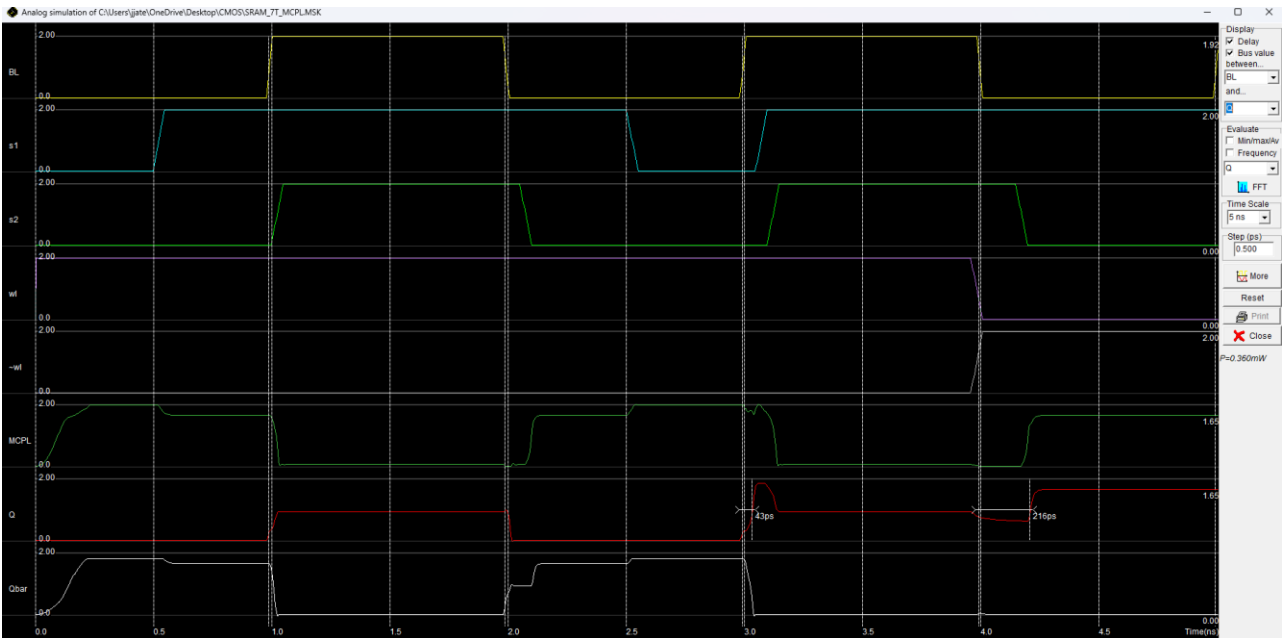
7T MCPL SRAM 2x2 Array Layout



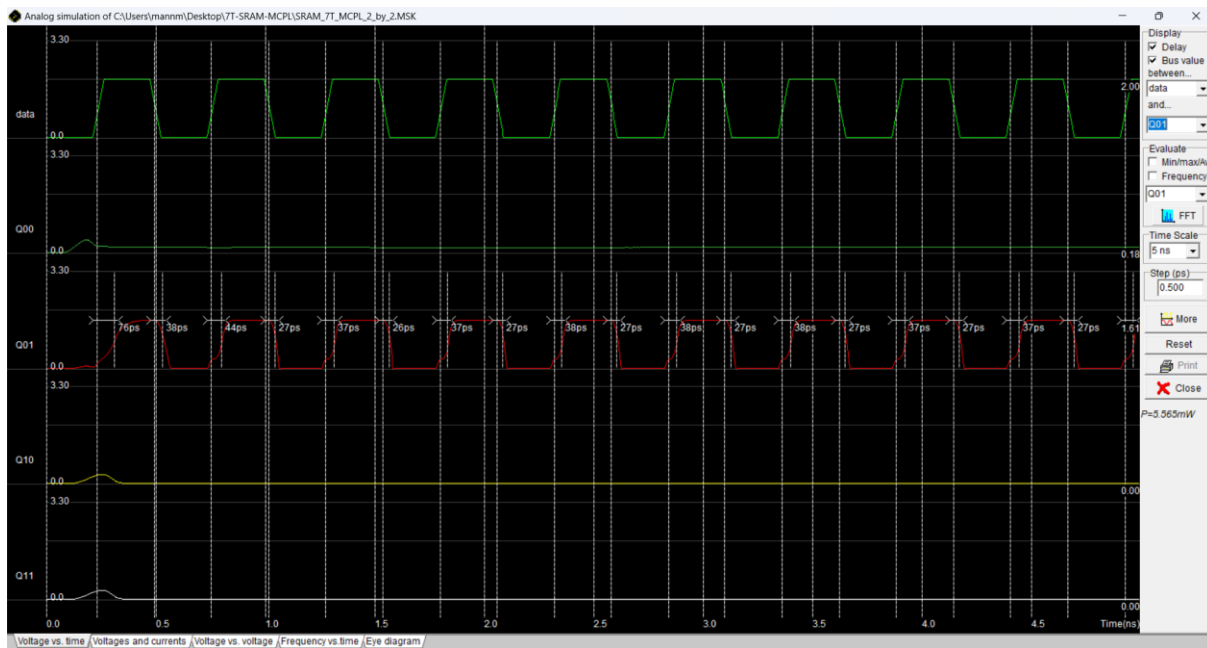
6T SRAM Waveforms



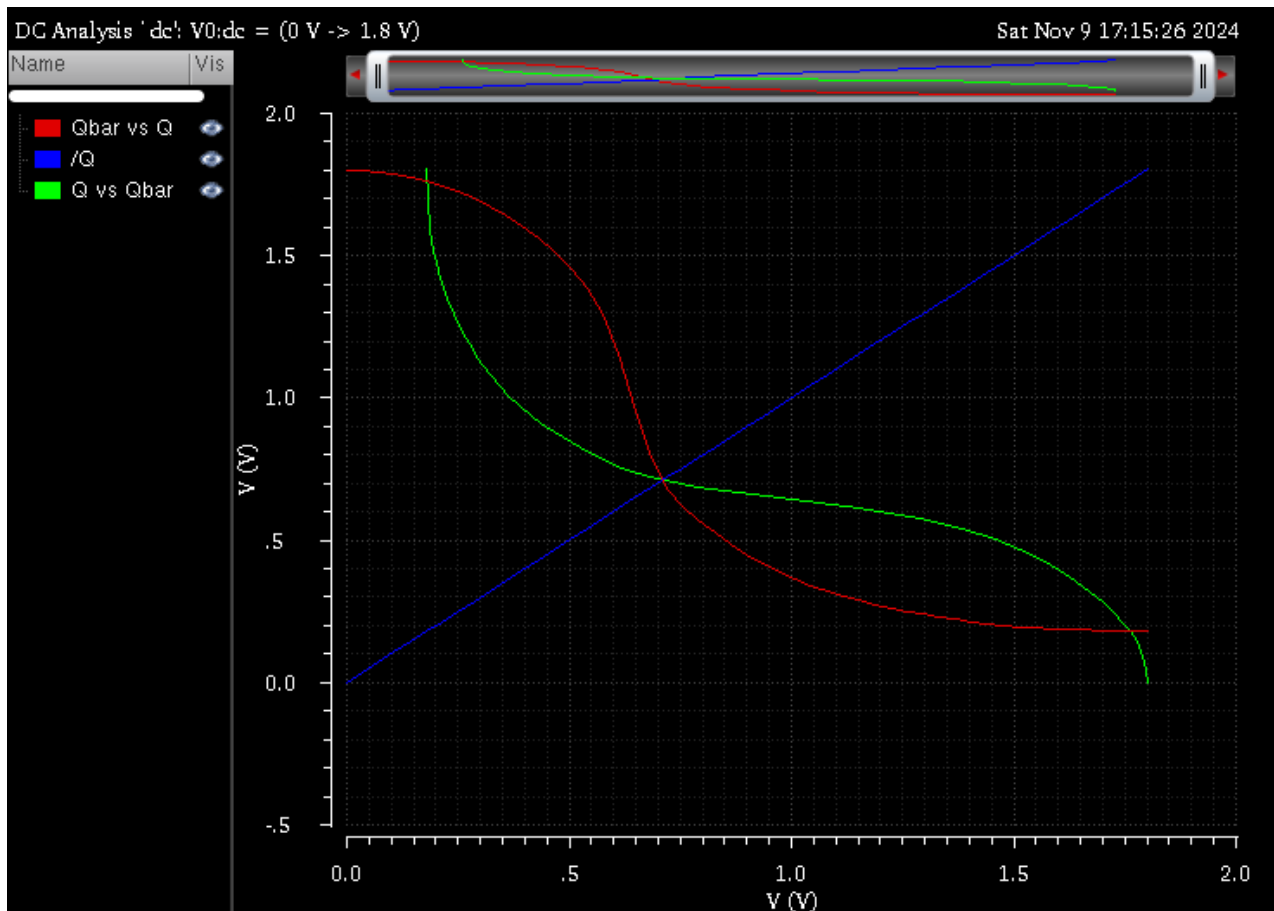
7T MCPL SRAM Waveforms



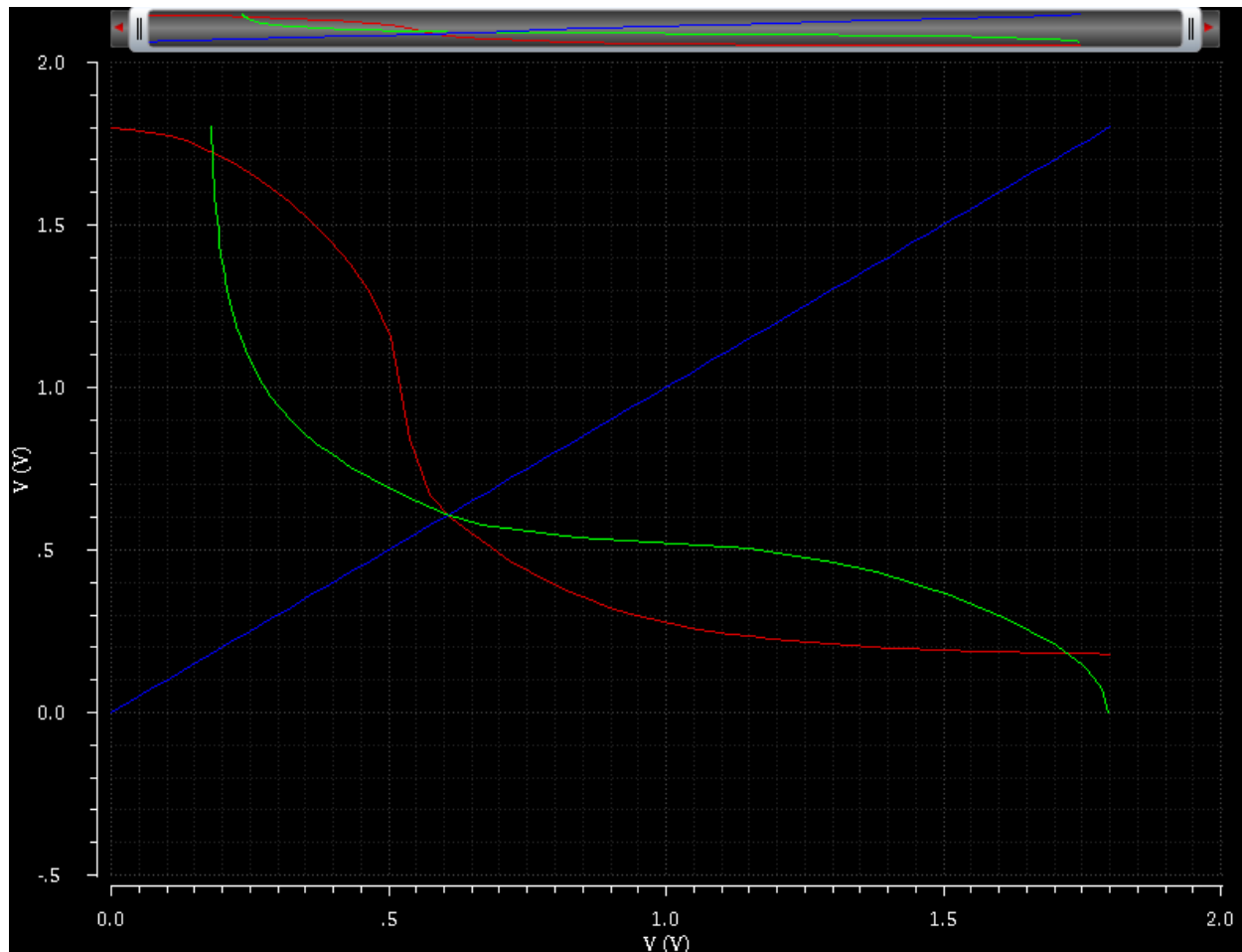
7T MCPL SRAM 2x2 Array Waveforms



6T SRAM SNM



7T MCPL SRAM SNM



Static Noise Margin (SNM) Analysis

From **Figures 8 and 9** in the referenced paper, we observe the stability of the **6T** and **7T MCPL SRAM** cells. The SNM, or Static Noise Margin, indicates the cell's resilience to noise and disturbances during read/write operations.

- **SNM is calculated** by connecting **DC voltages** on both sides of the inverter. The **butterfly diagram** is drawn by plotting the inverter voltage transfer characteristics. A **maximum square** is inscribed within the butterfly curve by moving the vertical and horizontal axes.
- In the SNM analysis:
 - The **6T SRAM** shows a smaller area in the butterfly curve, indicating lower stability.
 - The **7T MCPL SRAM** demonstrates a **0.3 times greater SNM** than the 6T SRAM, reflecting improved stability and noise tolerance.

This increase in SNM for the 7T MCPL SRAM is due to the added transistor and better isolation of the internal nodes during read/write operations, as explained in the **Why is the 7T MCPL SRAM more stable than the 6T SRAM?** section.

Performance Comparison

Power and Energy Consumption

Simulation results show a significant reduction in power and energy consumption using MCPL logic. Below are the power and energy figures for both designs under **180nm and 32nm technology**:

SRAM Cell	Power (W)	Energy (J)	Power (W) (32nm)	Energy (J) (32nm)
6T SRAM	85.6e-6	15.4e-9	4.6e-6	0.64e-12
6T SRAM with MCPL	26.9e-7	15.4e-15	2.34e-7	7.5e-15
6T SRAM with Transmission gate	24.05e-9	9.36e-15	12.2e-9	3.4e-15
7T SRAM	90.2e-6	6.32e-9	24.9e-6	13.4e-12
7T SRAM with MCPL	30.1e-7	117.9e-15	5.4e-7	40.5e-15

Stability (SNM)

The **Static Noise Margin (SNM)** analysis confirms that the **7T MCPL SRAM** design is **0.3 times more stable** than the 6T SRAM design. The improved stability comes at the cost of slightly higher power consumption, but this is offset by the energy reuse achieved through MCPL logic.

Why is the 7T MCPL SRAM more stable than the 6T SRAM?

1. Additional Transistor (7T Design):

- The **7T MCPL SRAM** includes an **additional transistor** compared to the **6T SRAM**. This extra transistor enhances the control over the internal nodes of the SRAM cell during read and write operations.
- The 6T SRAM has a greater tendency for **bitline disturbances** during read operations, which can lead to instability. By adding an extra transistor, the 7T SRAM isolates the bitlines better from the stored data, improving stability.

2. Improved Isolation:

- In the **6T SRAM**, both the **bitline** and the **cross-coupled inverters** are directly connected during read operations, which can cause the voltage at the storage nodes to fluctuate. This fluctuation reduces the stability of the cell.
- The **7T design**, particularly with **MCPL logic**, isolates the stored data more effectively by controlling the connection between the bitlines and the storage nodes, leading to higher SNM.

3. MCPL Adiabatic Logic:

- **Multi-Clock Power Logic (MCPL)** uses an **AC power supply** to control the power and ground connections in a dynamic way, which ensures smoother transitions of voltages during operations. This not only reduces power dissipation but also minimizes sudden voltage swings that can destabilize the cell.
- The controlled **power recycling** in MCPL logic reduces the chances of abrupt voltage changes, which might otherwise cause read or write failures. This results in better retention of the stored data, thus improving the **noise margin**.

How does this impact power consumption?

While the **7T MCPL SRAM** improves stability, it also introduces slightly higher power consumption due to: - **More active transistors**: The 7T design has an additional transistor that adds to the switching activity, leading to increased power consumption. - **Adiabatic logic overhead**: MCPL logic involves additional control signals (S1 and S2) and transistors that manage power recycling, which can slightly increase the dynamic power consumption.

However, **MCPL logic** helps **reuse energy**, significantly reducing overall power dissipation compared to a traditional 7T design. Thus, the small increase in dynamic power is compensated by the **energy reuse** and the improved **noise resilience** of the cell.

Conclusion

This project demonstrates the successful design and simulation of a **7T MCPL SRAM cell** using adiabatic logic. The MCPL-based design achieves over **90% reduction in power dissipation** compared to conventional 7T SRAM designs, while maintaining stability and performance.

Future Work

Further optimization of the 7T MCPL SRAM can focus on: 1. Reducing the area and parasitic capacitances. 2. Exploring the use of **FINFET** technology for lower power dissipation in sub-32nm nodes.

References

- [1] M. Beiser, "Low Power CMOS Circuits," IEEE Journal of Solid-State Circuits, vol. 35, no. 5, pp. 745-749, 2000.
 - [2] G. Alley, "Adiabatic Logic: A Survey," Proceedings of the IEEE, vol. 90, no. 3, pp. 339-358, March 2002.
 - [3] P. Meher, "CMOS VLSI Design," Addison-Wesley, 2008.
 - [4] Cadence Virtuoso, "Custom IC and PCB Design," Cadence Design Systems, Inc.
 - [5] This project is based on the work described in the following paper:

Penugonda, R.S., & Ravi, V. (2020). *Design of Low Power SRAM Cell Using Adiabatic Logic*. Journal of Physics: Conference Series, 1716(1), 012039.
doi:10.1088/1742-6596/1716/1/012039 **【6†source】**
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